## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10564837	HONGO ET AL.
Examiner	Art Unit

1796

SEARCHED				
Class	Subclass	Date	Examiner	
516	97	11/11/2008	/CCW/	

Chun-Cheng Wang

SEARCH NOTES			
Search Notes	Date	Examiner	
See EAST search history report	11/11/2008	/CCW/	
Inventor search	11/11/2008	/CCW/	
Japan patant search	11/11/2008	/CCW/	
Internet search about membrane integrity test and membrane	11/11/2008	/CCW/	
Internet search about membrane wash	6/17/2009	/CCW/	
See updated EAST search history report	6/17/2009	/CCW/	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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